

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|-------|------|--|--|------------------|---------|------------------|
| L1 | 0 | wafer and in-line and QC and test and (data near mining) and yield | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/05/13 12:57 |
| L2 | 5 | wafer and in-line and test and (data near mining) and yield | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/05/13 12:58 |
| L3 | 9044 | tai.in. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/05/13 13:36 |
| L4 | 8 | 3 and hung-en | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/05/13 13:36 |
| L5 | 1416 | 438/14.ccls. and wafer | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/05/13 14:38 |
| L6 | 94 | 5 and test and parameter and sample | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/05/13 14:38 |
| S1 | 16 | 702/84.ccls. and database and test and correlation | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/08/31 13:19 |
| S2 | 9 | 702/84.ccls. and database and test and analyze and correlation and wafer | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/08/27 09:56 |

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|-----|-------|---|---|----|----|------------------|
| S3 | 100 | 700/109.ccls. and wafer | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/08/31 13:58 |
| S4 | 669 | wafer and (quality near control) and analyzing | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/08/31 14:00 |
| S5 | 108 | (wafer and (quality near control) and analyzing) and parameter and lot and sample | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/08/31 14:19 |
| S6 | 9 | (quality adj control) same test same parameter same analyzing | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/05/13 08:59 |
| S7 | 505 | (quality adj control) and sample and parameter and search and database and analyzing | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/08/31 14:31 |
| S8 | 40 | ((quality adj control) and sample and parameter and search and database and analyzing) and correlating and predicting | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/08/31 14:32 |
| S9 | 113 | ((quality adj control) and sample and parameter and search and database and analyzing) and correlating | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/08/31 14:37 |
| S10 | 31 | ((quality adj control) and sample and parameter and search and database and analyzing) and ((quality adj control) and sample and parameter and search and database and analyzing) and correlating) and wafer | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/08/31 15:15 |
| S11 | 200 | wafer and in-line and yield and prediction | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/09/01 12:18 |
| S12 | 16493 | wafer and yield and analysis | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/09/01 12:19 |

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| S13 | 2711 | (wafer and yield and analysis) and statistical | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/09/01 12:19 |
| S14 | 665 | ((wafer and yield and analysis) and statistical) and regression | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/09/01 12:19 |
| S15 | 601 | ((wafer and yield and analysis) and statistical) and regression) and sample | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/09/01 12:20 |
| S16 | 409 | ((((wafer and yield and analysis) and statistical) and regression) and sample) and parameter | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/09/01 12:20 |
| S21 | 2 | "20050004773" | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/05/13 14:37 |
| S22 | 2 | (wafer or sample) and (in-line near QC near test) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/05/13 09:04 |
| S23 | 2 | wafer and (in-line near QC near test) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/05/13 09:04 |
| S24 | 51 | wafer and in-line and QC and test | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/05/13 12:57 |
| S25 | 2 | "6618682".pn. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/05/13 13:36 |

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| S26 | 2 | "6618682".uref. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/05/13 10:34 |
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